TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC74LCX02F,TC74LCX02FN,TC74LCX02FT

#### Low-Voltage Quad 2-Input NOR Gate with 5-V Tolerant Inputs and Outputs

The TC74LCX02 is a high-performance CMOS 2-input NOR gate. Designed for use in 3.3-V systems, it achieves high-speed operation while maintaining the CMOS low power dissipation.

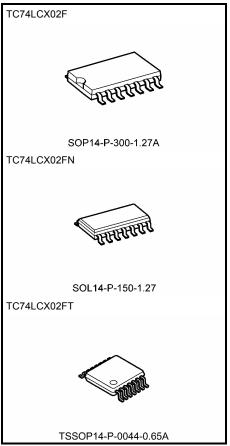
The device is designed for low-voltage (3.3 V)  $V_{\rm CC}$  applications, but it could be used to interface to 5-V supply environment for inputs

All inputs are equipped with protection circuits against static discharge.

#### **Features**

- Low-voltage operation: VCC = 2.0 to 3.6 V
- High-speed operation:  $t_{pd} = 5.2 \text{ ns (max) (VCC} = 3.0 \text{ to } 3.6 \text{ V)}$
- Output current:  $|I_{OH}|/I_{OL} = 24 \text{ mA (min) (V}_{CC} = 3.0 \text{ V)}$
- Latch-up performance: -500 mA
- · Available in JEDEC SOP, JEITA SOP and TSSOP
- · Power-down protection provided on all inputs and outputs
- Pin and function compatible with the 74 series (74AC/VHC/HC/F/ALS/LS etc.) 02 type

Note: xxxFN (JEDEC SOP) is not available in Japan.

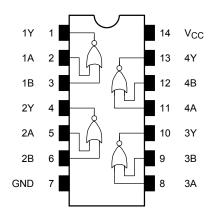


Weight

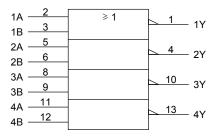
SOP14-P-300-1.27A : 0.18 g (typ.) SOL14-P-150-1.27 : 0.12 g (typ.) TSSOP14-P-0044-0.65A : 0.06 g (typ.)

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#### Pin Assignment (top view)



#### **IEC Logic Symbol**



#### **Truth Table**

Inp	outs	Outputs
Α	В	Y
L	L	Н
L	Н	L
Н	L	L
Н	Н	L

### **Absolute Maximum Ratings (Note 1)**

Characteristics	Symbol	Rating	Unit	
Power supply voltage	V <sub>CC</sub>	−0.5 to 7.0	V	
DC input voltage	V <sub>IN</sub>	-0.5 to 7.0	V	
		-0.5 to 7.0 (Note 2)		
DC output voltage	Vout	$-0.5$ to $V_{CC}$ + $0.5$ (Note 3)	V	
Input diode current	I <sub>IK</sub>	-50	mA	
Output diode current	lok	±50 (Note 4)	mA	
DC output current	lout	±50	mA	
Power dissipation	PD	180	mW	
DC V <sub>CC</sub> /ground current	I <sub>CC</sub> /I <sub>GND</sub>	±100	mA	
Storage temperature	T <sub>stg</sub>	-65 to 150	°C	

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2:  $V_{CC} = 0 V$ 

Note 3: High or low state. IOUT absolute maximum rating must be observed.

Note 4:  $V_{OUT} < GND, V_{OUT} > V_{CC}$ 



## **Operating Ranges (Note 1)**

Characteristics	Symbol	Rating	Unit	
Power supply voltage	V <sub>CC</sub>	2.0 to 3.6		
Tower supply voltage	VCC	1.5 to 3.6 (Note 2)	V	
Input voltage	V <sub>IN</sub>	0 to 5.5	V	
Output voltage	Vout	0 to 5.5 (Note 3)	V	
Output voltage		0 to V <sub>CC</sub> (Note 4)	V	
Output current	IOH/IOI	±24 (Note 5)	mA	
Output current	iOH/iOL	±12 (Note 6)	IIIA	
Operating temperature	T <sub>opr</sub>	-40 to 85	°C	
Input rise and fall time	dt/dv	0 to 10 (Note 7)	ns/V	

Note 1: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs must be tied to either VCC or GND.

Note 2: Data retention only

Note 3:  $V_{CC} = 0 V$ 

Note 4: High or low state

Note 5:  $V_{CC} = 3.0 \text{ to } 3.6 \text{ V}$ 

Note 6:  $V_{CC} = 2.7$  to 3.0 V

Note 7:  $V_{IN} = 0.8$  to 2.0 V,  $V_{CC} = 3.0$  V

### **Electrical Characteristics**

### DC Characteristics ( $Ta = -40 \text{ to } 85^{\circ}\text{C}$ )

Characteristics		Symbol	Symbol Test Condition		V <sub>CC</sub> (V)	Min	Max	Unit
Input voltage H-level		$V_{IH}$	_		2.7 to 3.6	2.0	_	V
input voltage	L-level	VIL	_		2.7 to 3.6	l	0.8	٧
			$V_{IN} = V_{IL}$	$I_{OH} = -100 \mu A$	2.7 to 3.6	V <sub>CC</sub> - 0.2		
	H-level	V <sub>OH</sub>		$I_{OH} = -12 \text{ mA}$	2.7	2.2	_	
				$I_{OH} = -18 \text{ mA}$	3.0	2.4	_	
Output voltage				$I_{OH} = -24 \text{ mA}$	3.0	2.2	_	
L-level		-level V <sub>OL</sub>	$V_{IN} = V_{IH}$ or $V_{IL}$	I <sub>OL</sub> = 100 μA	2.7 to 3.6	_	0.2	
	Llovel			$I_{OL} = 12 \text{ mA}$	2.7	_	0.4	
	L-level			$I_{OL} = 16 \text{ mA}$	3.0	_	0.4	
				$I_{OL} = 24 \text{ mA}$	3.0	_	0.55	
Input leakage current		I <sub>IN</sub>	V <sub>IN</sub> = 0 to 5.5 V	•	2.7 to 3.6	_	±5.0	μА
Power-off leakage cur	rent	l <sub>OFF</sub>	$V_{IN}/V_{OUT} = 5.5 \text{ V}$		0	_	10.0	μΑ
Quiescent supply current	Icc	V <sub>IN</sub> = V <sub>CC</sub> or GND		2.7 to 3.6	_	10.0		
		V <sub>IN</sub> = 3.6 to 5.5 V		2.7 to 3.6	_	±10.0	μΑ	
Increase in Icc per inp	ut	Δlcc	$V_{IH} = V_{CC} - 0.6 V$		2.7 to 3.6	_	500	



#### AC Characteristics ( $Ta = -40 \text{ to } 85^{\circ}\text{C}$ )

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Min	Max	Unit
Propagation delay time	t <sub>pLH</sub>	Figure 1, Figure 2	2.7	_	6.0	ns
	$t_{pHL}$		$3.3 \pm 0.3$	1.5	5.2	
Output to output skew	t <sub>osLH</sub>	(Note)	2.7	1		20
	t <sub>osHL</sub>		$3.3 \pm 0.3$	_	1.0	ns

Note: Parameter guaranteed by design.

 $(t_{OSLH} = |t_{PLHm} - t_{PLHn}|, t_{OSHL} = |t_{PHLm} - t_{PHLn}|)$ 

### Dynamic Switching Characteristics (Ta = 25°C, input: $t_r = t_f = 2.5$ ns, $C_L = 50$ pF, $R_L = 500$ $\Omega$ )

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Тур.	Unit
Quiet output maximum dynamic V <sub>OL</sub>	V <sub>OLP</sub>	$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$	3.3	8.0	V
Quiet output minimum dynamic $V_{\mbox{OL}}$	V <sub>OLV</sub>	$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$	3.3	8.0	V

#### **Capacitive Characteristics (Ta = 25°C)**

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Тур.	Unit
Input capacitance	C <sub>IN</sub>	_	3.3	7	pF
Output capacitance	C <sub>OUT</sub>	_	0	8	pF
Power dissipation capacitance	C <sub>PD</sub>	f <sub>IN</sub> = 10 MHz (Note	3.3	25	pF

Note: CPD is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

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Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC} / 4 \text{ (per gate)}$ 

### **AC Test Circuit**

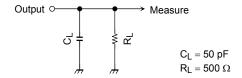


Figure 1

### **AC Waveform**

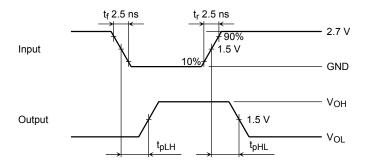
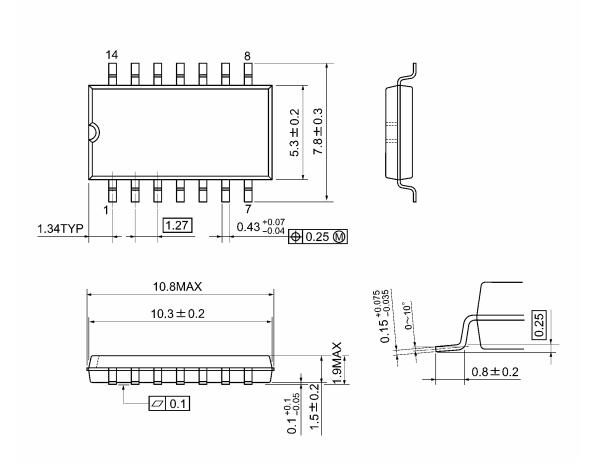


Figure 2  $t_{pLH}, t_{pHL}$ 

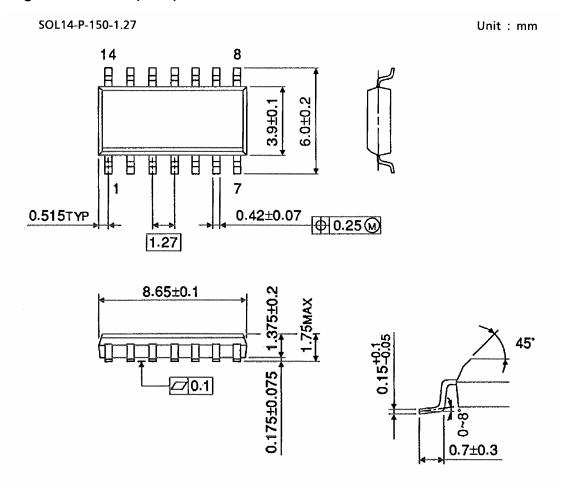
## **Package Dimensions**

SOP14-P-300-1.27A Unit: mm



Weight: 0.18 g (typ.)

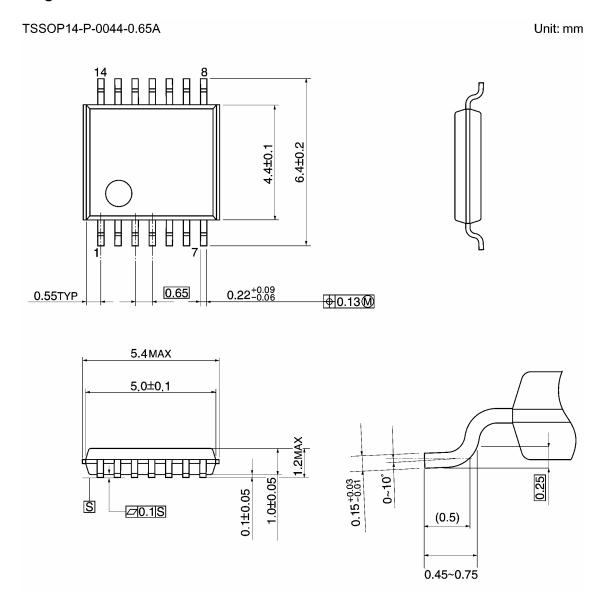
## **Package Dimensions (Note)**



Note: This package is not available in japan.

Weight: 0.12 g (typ.)

## **Package Dimensions**



Weight: 0.06 g (typ.)

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20070701-EN GENERAL

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